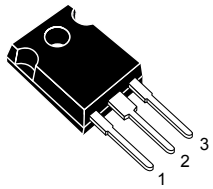
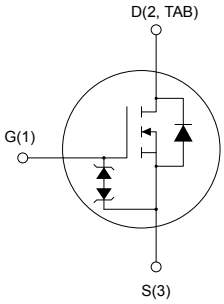
N-channel 1200 V, 1.65 Ω typ., 6 A, MDmesh K5 Power MOSFET in a TO-247 package



TO-247



AM01476v1_tab

Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D	P_{TOT}
STW8N120K5	1200 V	2.00 Ω	6 A	130 W

- Very low FoM (figure of merit)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Product status link
STW8N120K5

Product summary	
Order code	STW8N120K5
Marking	8N120K5
Package	TO-247
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	±30	V
I_D	Drain current (continuous) at T_C = 25 °C	6	A
	Drain current (continuous) at T_C = 100 °C	3.5	A
I_{DM}(1)	Drain current pulsed	12	A
P_{TOT}	Total dissipation at T_C = 25 °C	130	W
dv/dt(2)	Peak diode recovery voltage slope	4.5	V/ns
dv/dt(3)	MOSFET dv/dt ruggedness	50	
T_J	Operating junction temperature range	-55 to 150	°C
T_{stg}	Storage temperature range		

1. *Pulse width limited by safe operating area*
2. *I_{SD} ≤ 6 A, di/dt ≤ 100 A/µs, V_{DS} peak ≤ $V_{(BR)DSS}$*
3. *V_{DD} ≤ 960 V*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	0.96	°C/W
R_{thJA}	Thermal resistance, junction-to-ambient	50	°C/W

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_{jmax})	1.7	A
E_{AS}	Single-pulse avalanche energy (starting T_J = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	415	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	1200			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 1200 V			1	µA
		V_{GS} = 0 V, V_{DS} = 1200 V T_C = 125 °C (1)			50	µA
I_{GSS}	Gate body leakage current	V_{DS} = 0 V, V_{GS} = ±20 V			±10	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 100 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 2.5 A		1.65	2.00	Ω

1. *Specified by design, not tested in production.*

Table 5. Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, V_{GS} = 0 V, f = 1 MHz	-	505	-	pF
C_{oss}	Output capacitance		-	44	-	pF
C_{rss}	Reverse transfer capacitance		-	0.4	-	pF
$C_{o(tr)}$ (1)	Time-related equivalent capacitance	V_{DS} = 0 to 960 V, V_{GS} = 0 V	-	70	-	pF
$C_{o(er)}$ (2)	Energy-related equivalent capacitance		-	24	-	pF
R_g	Intrinsic gate resistance	f = 1 MHz , I_D = 0 A	-	7.7	-	Ω
Q_g	Total gate charge	V_{DD} = 960 V, I_D = 5 A V_{GS} = 0 to 10 V (see Figure 14. Test circuit for gate charge behavior)	-	13.7	-	nC
Q_{gs}	Gate-source charge		-	3.6	-	nC
Q_{gd}	Gate-drain charge		-	7.1	-	nC

1. *$C_{o(tr)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*
2. *$C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD} = 600 V, I_D = 2.5 A, R_G = 4.7 Ω, V_{GS} = 10 V (see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	15.5	-	ns
t_r	Rise time		-	11	-	ns
$t_{d(off)}$	Turn-off delay time		-	40	-	ns
t_f	Fall time		-	27	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		6	A
I_{SDM}(1)	Source-drain current (pulsed)		-		12	A
V_{SD}(2)	Forward on voltage	I_{SD} = 5 A, V_{GS} = 0 V	-		1.5	V
t_{rr}	Reverse recovery time	I_{SD} = 5 A, V_{DD} = 60 V, di/dt = 100 A/µs (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	327		ns
Q_{rr}	Reverse recovery charge		-	3		µC
I_{RRM}	Reverse recovery current		-	18.4		A
t_{rr}	Reverse recovery time	I_{SD} = 5 A, V_{DD} = 60 V, di/dt = 100 A/µs, T_j = 150 °C (see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	485		ns
Q_{rr}	Reverse recovery charge		-	3.9		µC
I_{RRM}	Reverse recovery current		-	16		A

1. *Pulse width limited by safe operating area.*
2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%.*

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

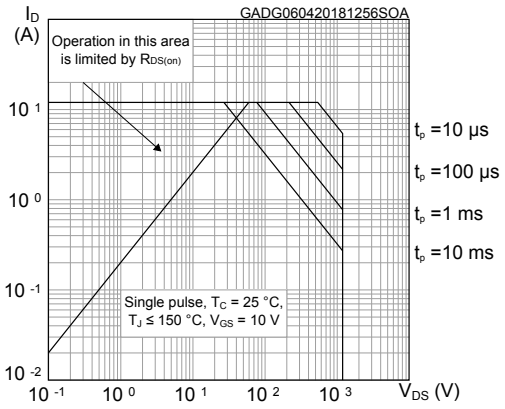


Figure 2. Thermal impedance

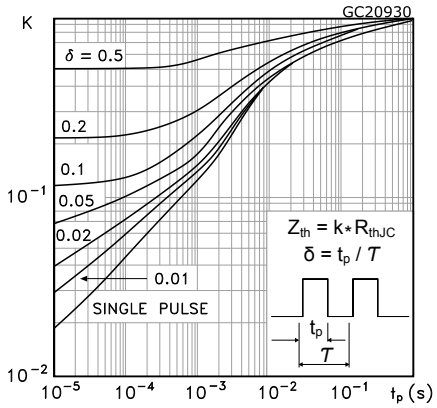


Figure 3. Output characteristics

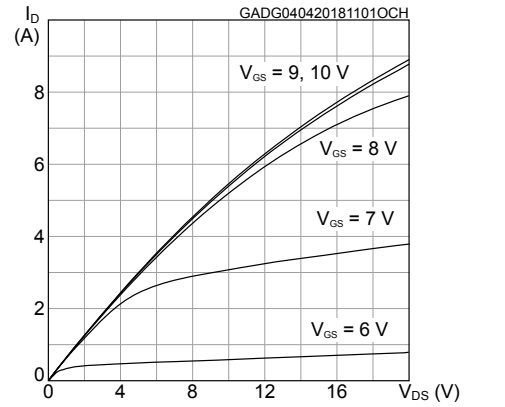


Figure 4. Transfer characteristics

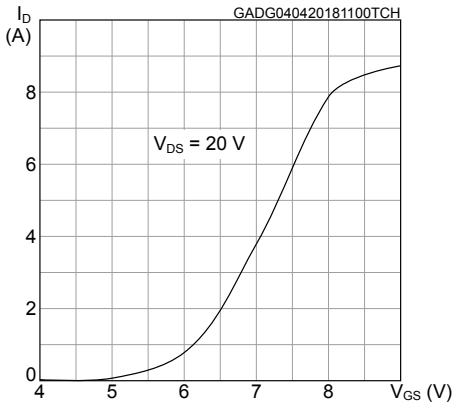


Figure 5. Gate charge vs gate-source voltage

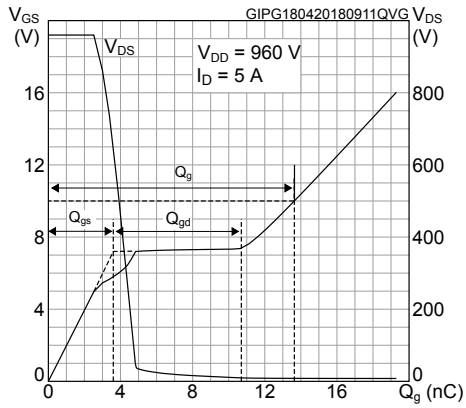


Figure 6. Static drain-source on-resistance

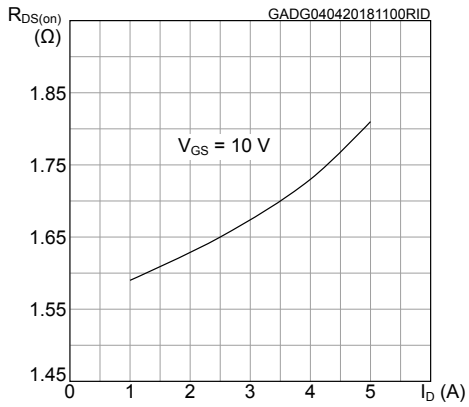


Figure 7. Capacitance variations

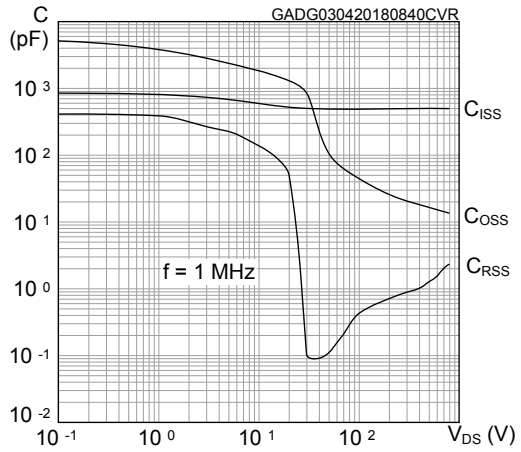


Figure 8. Normalized gate threshold voltage vs temperature

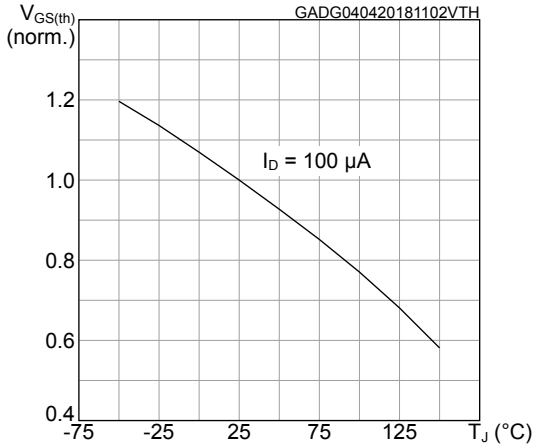


Figure 9. Normalized on-resistance vs temperature

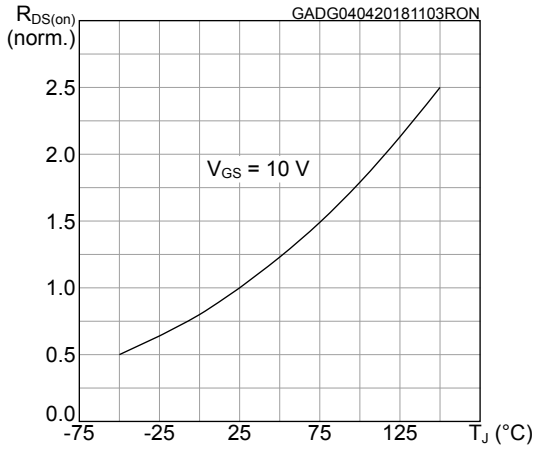


Figure 10. Normalized $V_{(BR)DSS}$ vs temperature

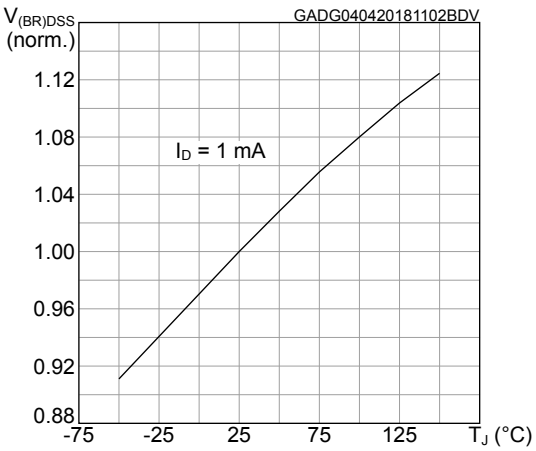


Figure 11. Source-drain diode forward characteristics

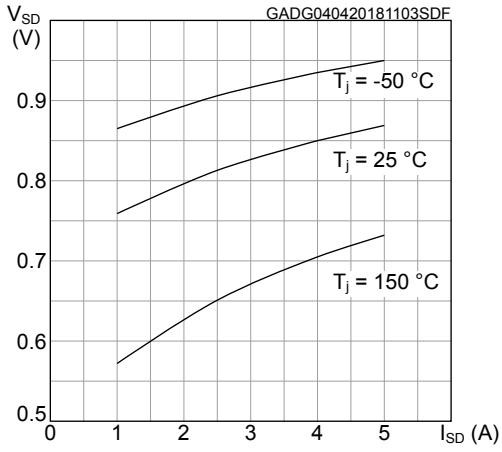
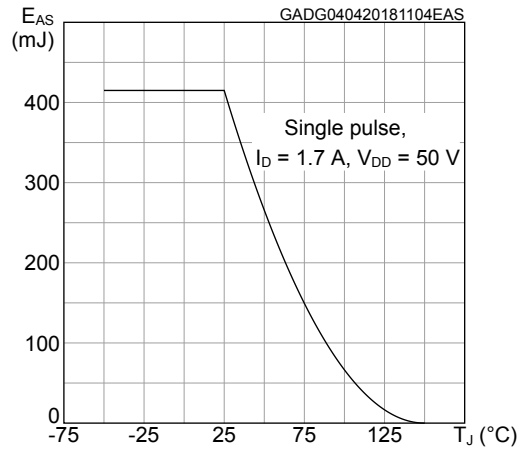
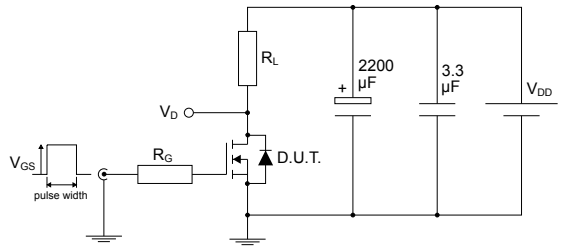


Figure 12. Maximum avalanche energy vs starting T_J



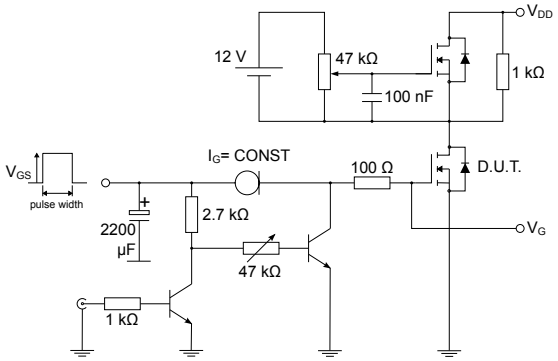
3 Test circuits

Figure 13. Test circuit for resistive load switching times



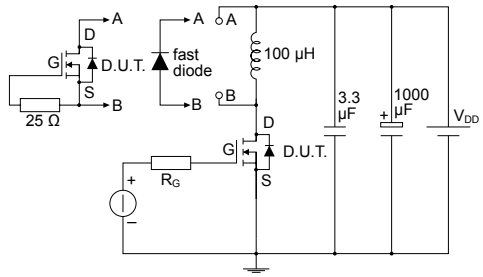
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Figure 14. Test circuit for gate charge behavior



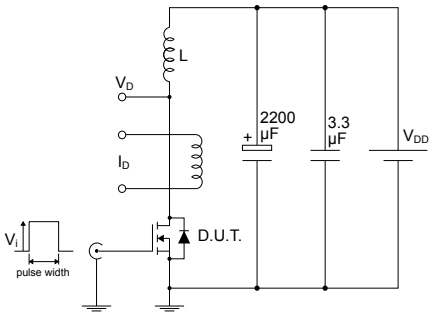
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Figure 15. Test circuit for inductive load switching and diode recovery times



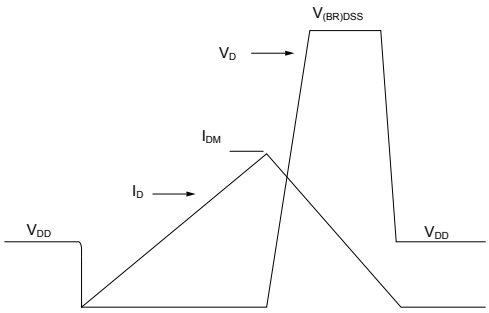
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Figure 16. Unclamped inductive load test circuit



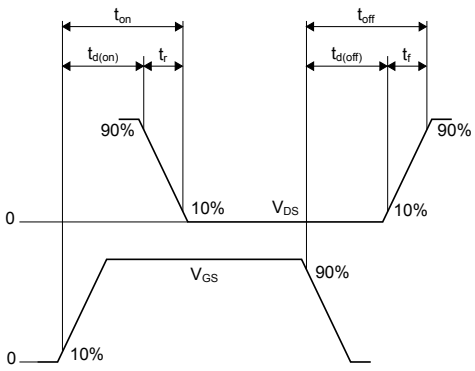
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Figure 17. Unclamped inductive waveform



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Figure 18. Switching time waveform



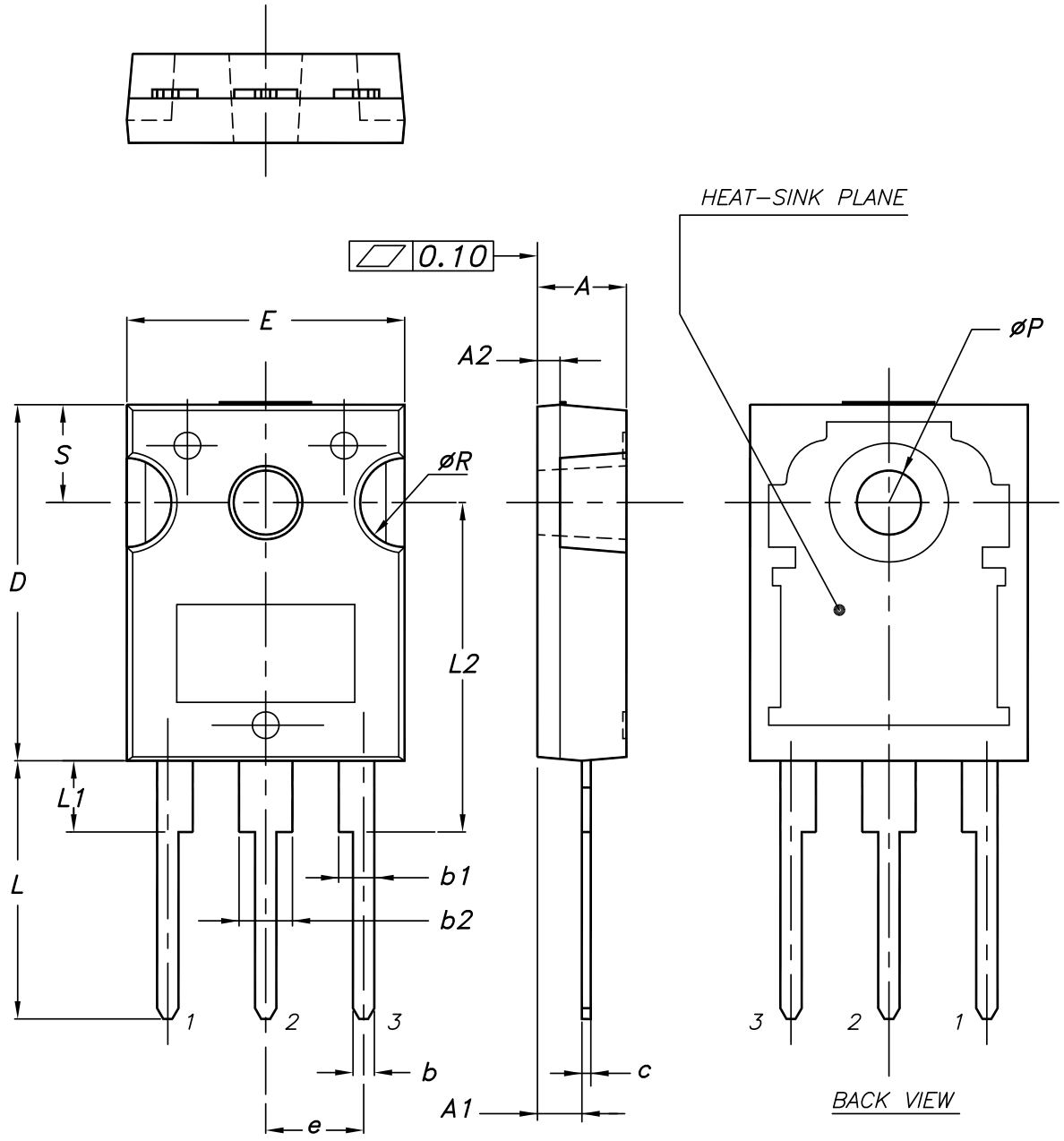
AM01473v1

4 Package information

To meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions, and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-247 package information

Figure 19. TO-247 package outline



0075325_11

Table 8. **TO-247 package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
A2		1.27	
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Revision history

Table 9. **Document revision history**

Date	Version	Changes
09-Apr-2018	1	Initial release. The document status is preliminary data.
17-Apr-2018	2	Modified *Table 5. Dynamic characteristics* and *Figure 5. Gate charge vs gate-source voltage*. Minor text changes.
30-May-2018	3	Document status promoted from preliminary to production data.
05-Dec-2025	4	Updated Section 4: Package information. Minor text changes.

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